

Docket No. 250847US2X

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

IN RE APPLICATION OF: Sotoshi YAMADA, et al.

SERIAL NO: New Application

GAU:

FILED: Herewith

EXAMINER:

FOR: EDDY-CURRENT SENSOR FOR NONDESTRUCTIVE TESTING

**INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR 1.97**

COMMISSIONER FOR PATENTS  
ALEXANDRIA, VIRGINIA 22313

SIR:

Applicant(s) wish to disclose the following information.

**REFERENCES**

- ☒ The applicant(s) wish to make of record the references listed on the attached form PTO-1449. Copies of the listed references are attached, where required, as are either statements of relevancy or any readily available English translations of pertinent portions of any non-English language references.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

**RELATED CASES**

- ☐ Attached is a list of applicant's pending application(s) or issued patent(s) which may be related to the present application. A copy of the patent(s), together with a copy of the claims and drawings of the pending application(s) is attached along with PTO 1449.
- ☐ A check or credit card payment form is attached in the amount required under 37 CFR §1.17(p).

**CERTIFICATION**

- ☐ Each item of information contained in this information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of this statement.
- ☐ No item of information contained in this information disclosure statement was cited in a communication from a foreign patent office in a counterpart foreign application or, to the knowledge of the undersigned, having made reasonable inquiry, was known to any individual designated in 37 CFR §1.56(c) more than three months prior to the filing of this statement.

**DEPOSIT ACCOUNT**

- ☒ Please charge any additional fees for the papers being filed herewith and for which no check or credit card payment is enclosed herewith, or credit any overpayment to deposit account number 15-0030. A duplicate copy of this sheet is enclosed.

Respectfully submitted,

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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. <b>250847US2X</b>		SERIAL NO. <b>New Application</b>	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT <b>Sotoshi YAMADA, et al.</b>			
				FILING DATE <b>Herewith</b>		GROUP	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES                      NO		
	AF	7-83884	03/31/95	Japan (with English Abstract)			x
	AG	9-189682	07/22/97	Japan (with English Abstract)			x
	AH	11-248685	09/17/99	Japan (with English Abstract)			x
	AI	2002-90490	03/27/02	Japan (with English Abstract)			x
	AJ						
	AK						
	AL						
	AM						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AN	Y. KATAOKA, et al. "Application of GMR Line Sensor to Eddy Current Testing Probe", JOURNAL OF THE MAGNETICS SOCIETY OF JAPAN, Vol. 27, No. 4, pp. 385-388, April 1, 2003					
	AO	Y. KATAOKA, et al. " Application of GMR Line Sensor to Eddy Current Testing", DIGESTS OF INTERMAG 2003, IEEE, CQ-07, April, 2003					
	AP	Sotoshi YAMADA, et al. "Inspection of Bare Printed Circuit Board Using Planar Type ECT Probe", REVIEW OF PROGRESS IN QUANTITATIVE NDE, P. 9, July 28, 2003					
	AQ	Yuzo FUKUDA, et al. " High Frequency and Small Field Amplitude Characteristics of GMR-SV Sensor for Eddy Current Testing", THE 27TH ANNUAL CONFERENCE OF MAGNETICS IN JAPAN, 19pC-1, p. 472, September 19, 2003					
	AR	K. CHOMUSUWAN, et al. "The GMR Sensor Utilization for PCB Inspection Based on Eddy-Current Testing Technique", THE 27TH ANNUAL CONFERENCE OF MAGNETICS IN JAPAN, 19pC-2, p. 473, September 19, 2003					
	AS	Y. FUKUDA, et al. "High-Frequency, Low-Amplitude Magnetic Field Characteristics of SV-GMR Sensor for ECT Technique", JOURNAL OF THE MAGNETICS SOCIETY OF JAPAN, Vol. 28, No. 3, pp. 405-408, March 1, 2004					
	AT	K. CHOMSUNAN, et al. " GMR Sensor Utilization for PCB Inspection Based on the Eddy-Current Testing Technique", TRANSACTIONS OF THE MAGNETICS SOCIETY OF JAPAN, Vol. 4, No. 1, pp. 39-42, February 1, 2004					
	AU	T. MIYAGOSHI, et al. "Feasibility of Inspecting Defects in Printed Circuit Boards by Using Eddy-Current Testing Techniques", JOURNAL OF THE MAGNETICS SOCIETY OF JAPAN, Vol. 23, No. 4-2, pp. 1613-1616, 1999					
	UV	S. YAMADA, et al. " Trend of Detection Techniques Using Planar-Type Micro-Eddy-Current Testing Probes", JOURNAL OF THE MAGNETICS SOCIETY OF JAPAN, Vol. 23, No. 7, pp. 1817-1825, 1999					
	AW						<input type="checkbox"/> Additional References sheet(s) attached
Examiner					Date Considered		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							